Special Issue

Advanced Methods and Applications of AI Diagnostic

Message from the Guest Editor

AI techniques-based diagnostics have the potential to provide high reliability in practical diseases and symptoms management. The rapid growth of medical multimedia data not only gives a chance to improve AI diagnostic quality but also to discover advance knowledge of rare diseases and symptoms. Over the past few years, improvements in computing power and diverse machine learning techniques enable us to process hundreds of thousands of multimedia data and extract expert knowledge for a medical diagnosis. The main topics include but are not limited to the following:

- Advanced methods of medical image processing and analysis
- Early detection and diagnosis methods for diverse symptoms management
- Multimedia big data processing for diagnosis applications
- Pattern recognition techniques for clinical diagnosis
- AI-based symptoms and disease monitoring or management

Guest Editor

Dr. Seungmin Rho
Department of Industrial Security, Chung-Ang University, Seoul 06974, Republic of Korea

---

Deadline for manuscript submissions

closed (31 August 2020)

Applied Sciences

an Open Access Journal by MDPI

Impact Factor 2.5
CiteScore 5.5

mdpi.com/si/38805

Applied Sciences
Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland
Tel: +41 61 683 77 34
applsci@mdpi.com

mdpi.com/journal/applsci

Applied
Sciences

an Open Access Journal
by MDPI

Impact Factor 2.5
CiteScore 5.5

mdpi.com/journal/applsci

MDPI

About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32,
20133 Milano, Italy

Author Benefits

Open Access:

free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility:

indexed within Scopus, SCIE (Web of Science), Ei Compendex, Inspec, CAPlus / SciFinder, and other databases.

Journal Rank:

JCR - Q2 (Engineering, Multidisciplinary) / CiteScore - Q1 (General Engineering)